Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10552947	BARKER, RICHARD J.
Examiner	Art Unit
Nguyen, Hiep	2816

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST (see attachment)	11-18-08	Hn	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
327	423,427,430,434-437,108,538,50,541	11-18-08	Hn	
361	91.1	11-18-08	Hn	

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